

Errata

Erratum to “A Test Response Compression Method for Monolithic 3-D ICs Based on 3-D Haar Wavelet Transforms”

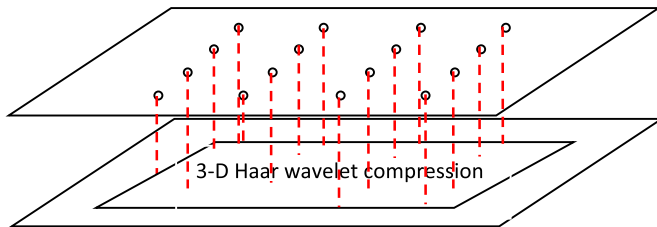
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In the above article [1], the following sentence on page 5, right column, has been corrected to read as follows: for two detected faults in the Fig. 11(a) and (c) case, even if there is a big difference between their measurement values, they will have the same saved data.

On Page 5, right column, Line 19: “[‘b11 × 0, ‘b00 × 0, ‘b00 × 0, −2]” should be “[‘b11x0, ‘b00x0, ‘b00x0, −2].”

Page 5, right column, Line 25: “[‘b00 × 0, ‘b01 × 0, ‘b00 × 0, −2]” should be “[‘b00x0, ‘b01x0, ‘b00x0, −2].”

Page 5, left column, Fig. 8: The length of the red dotted line should be as follows:



Page 9, right column, Line 25:

$$\left(\frac{1 - \text{compressed data}}{\text{precompression data}} \right) \times 100\%$$

should be

$$\left(1 - \frac{\text{compressed data}}{\text{precompression data}} \right) \times 100\%.$$

REFERENCES

- [1] J. Hu, Y. Lin, M. Hu, and H. Wang, “A test response compression method for monolithic 3-D ICs based on 3-D haar wavelet transforms,” *IEEE Trans. Instrum. Meas.*, vol. 70, no. 1, 2021, Art. no. 3506412.

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